Issue Classification

Application/Control No.	Applicant(s)/Patent Under Reexamination
10632665	HAPARNAS ET AL.
Examiner	**Art Unit**
Chen, Shin-Hon	2131

ORIGINAL	
CLASS	SUBCLASS
713	168

CROSS REFERENCE(S)

CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
380	247	270			
713	155				
455	41.2	411	410	517	466

INTERNATIONAL CLASSIFICATION

CLAIMED	NON-CLAIMED
H 04L 9/00 (2006.01.01)	H 04B 7/00 (2006.01.01)
H 04K 1/00 (2006.01.01)	H 04B 1/00 (2006.01.01)
H 04K 1/02 (2006.01.01)	H 04B 15/00 (2006.01.01)
H 04M 1/68 (2006.01.01)	H 04Q 7/20 (2006.01.01)
H 04M 1/66 (2006.01.01)	
H 04M 3/16 (2006.01.01)	

Chen, Shin-Hon (Assistant Examiner)	12/5/07 (Date)	**Total Claims Allowed:** 26
(Legal Instruments Examiner)	12/20/07 (Date)	O.G. Print Claim(s): 1 — O.G. Print Figure: 5

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